

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/666,147	DEB ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Helen C. Kwok	2856	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
73	514.32	11/23/2005	HK
73	504.14	11/23/2005	HK